

Diode Modeling

(Part 2)

Dr. José Ernesto Rayas Sánchez

Some figures of this presentation were taken from the instructional resources of the following textbooks:

A. S. Sedra and K. C. Smith, *Microelectronic Circuits*. New York, NY: Oxford University Press, 2003.

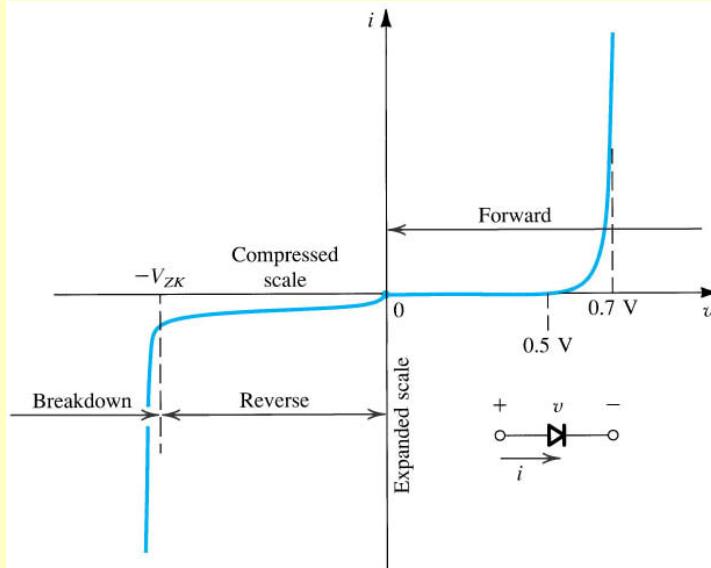
A. R. Hambley, *Electronics: A Top-Down Approach to Computer-Aided Circuit Design*. Englewood Cliffs, NJ: Prentice Hall, 2000.

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Outline

- Temperature effects on I-V characteristics
- Modeling temperature effects on forward characteristics
- Using diodes as temperature sensors
- Modeling temperature effects on reverse characteristics
- Models for small-signal forward region, low/high frequency
- Models for small-signal reverse region, low/high frequency
- Charge storage effects

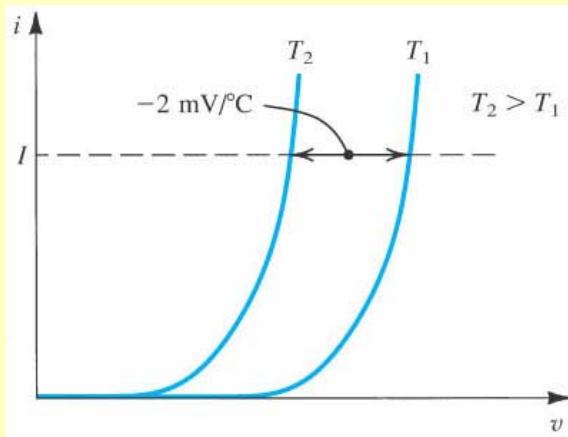
I-V Characteristics



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Temperature Effects on Forward Characteristics



- For a constant i_D , v_D decreases linearly with temperature
- For a constant v_D , i_D is very sensitive to temperature; it increases nonlinearly with temperature

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Temperature Effects from Shockley Equation

$$i_D = I_S \left(e^{\frac{V_D}{\eta V_T}} - 1 \right)$$

In the forward region, $i_D \approx I_S e^{\frac{V_D}{\eta V_T}}$

$$V_T = \frac{kT}{q} \approx \frac{T}{11,594} \quad V_T \text{ increases linearly with temperature}$$

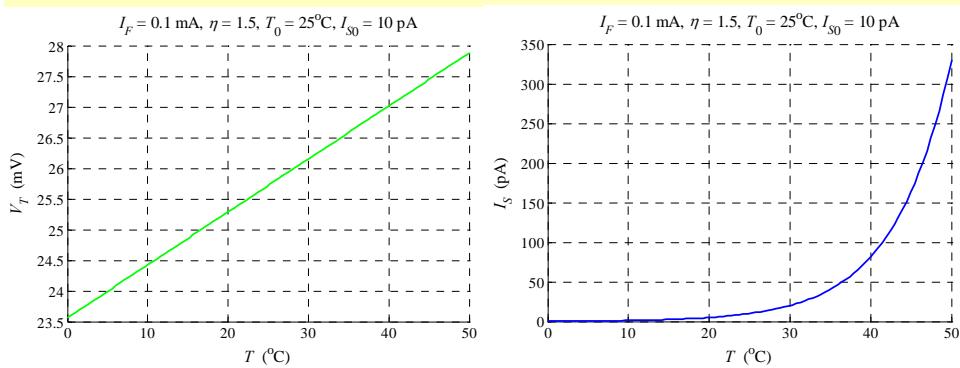
I_S increases nonlinearly with temperature; it increases by 15% per °C rise in temperature

$$I_S(T) = I_S(T_0) \times (1.15)^{(T-T_0)}$$

Plotting v_D VS Temperature ($i_D = \text{constant}$)

$$v_D = \eta V_T \ln\left(\frac{i_D}{I_S}\right) \quad V_T = \frac{kT}{q} \quad I_S(T) = I_S(T_0) \times (1.15)^{(T-T_0)}$$

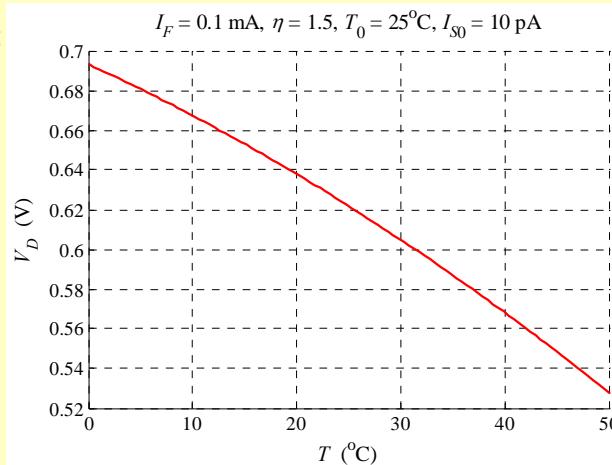
Example:



Plotting v_D VS Temperature ($i_D = \text{constant}$)

$$v_D = \eta V_T \ln\left(\frac{i_D}{I_S}\right) \quad V_T = \frac{kT}{q} \quad I_S(T) = I_S(T_0) \times (1.15)^{(T-T_0)}$$

Example:



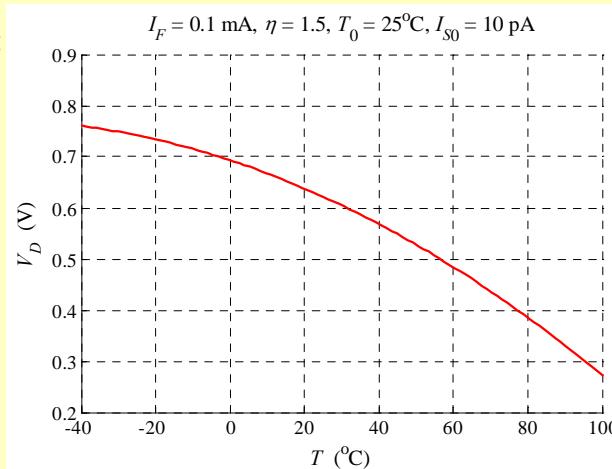
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Plotting v_D VS Temperature ($i_D = \text{constant}$)

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Example:

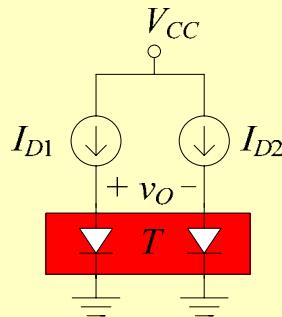


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Using Diodes as Temperature Sensors

- If temperature variation is large, the forward v_D (keeping I_D constant) is no longer a linear function of temperature
- To measure temperature more effectively (linear sensor):



Assuming identical diodes:

$$v_o = \left[\frac{\eta k}{q} \ln \left(\frac{I_{D1}}{I_{D2}} \right) \right] T$$

Temperature Effects on Reverse Characteristics

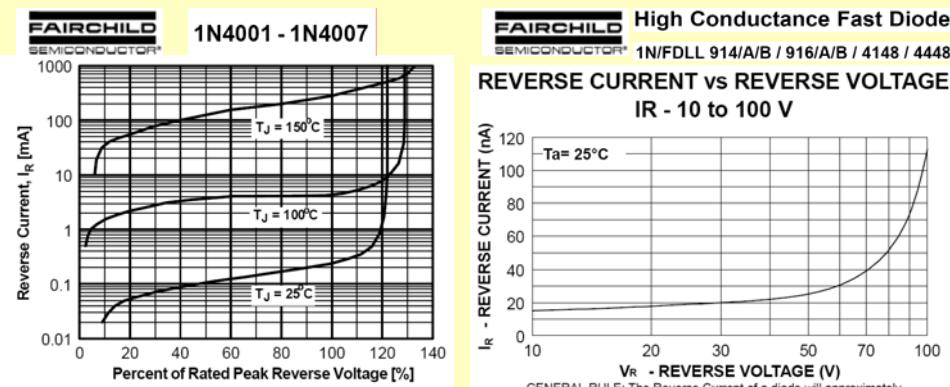
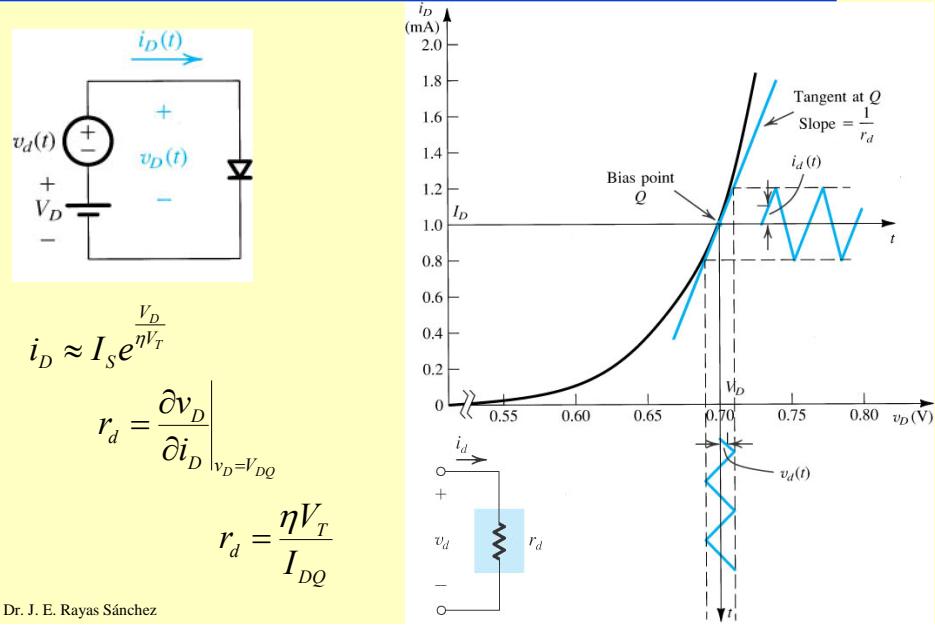


Figure 4. Reverse Current vs Reverse Voltage

I_R increases nonlinearly with temperature; it increases by 100% per 10 °C rise in temperature

$$I_S(T) = I_S(T_0) \times 2^{\left(\frac{T-T_0}{10}\right)}$$

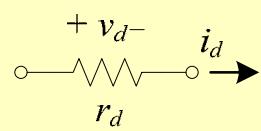
Diode Small-Signal Model – Forward Region



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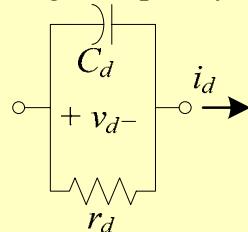
Diode Small-Signal Model – Forward Region

- Low-frequency



$$r_d = \frac{\eta V_T}{I_{DQ}}$$

- High-frequency

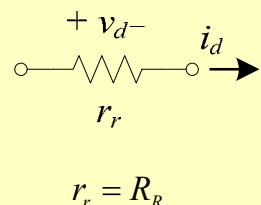


$$C_d = K_d I_{DQ}$$

K_d is a constant that depends on the junction cross-section area and diode materials

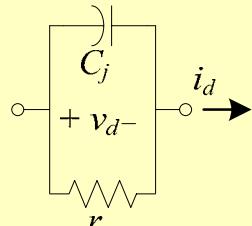
Diode Small-Signal Model – Reverse Region

- Low-frequency



$$r_r = R_R$$

- High-frequency



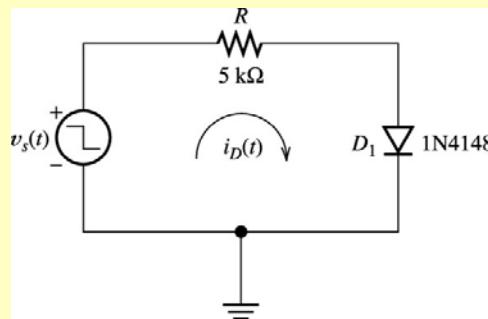
$$C_j = \frac{C_{j0}}{\sqrt{\psi_0 - V_{DQ}}} \quad (V_{DQ} < 0)$$

- C_{j0} is a constant that depends on the junction cross-section area and diode materials
- ψ_0 is the built-in potential, that depends on the doping characteristics

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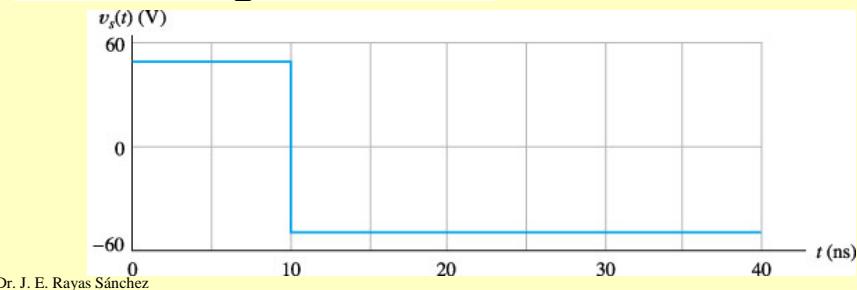
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Effects of C_j , C_d , and Charge Storage – Example



$$i_D(t) = ?$$

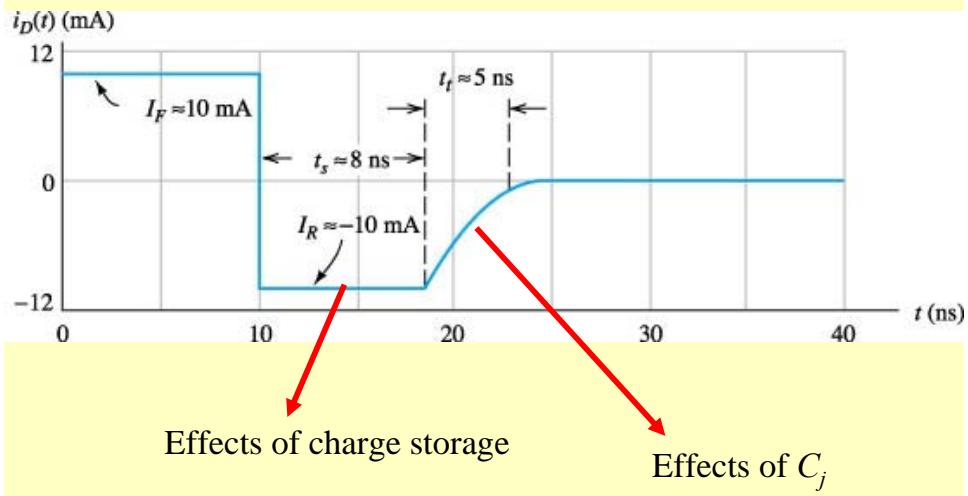
$$v_D(t) = ?$$



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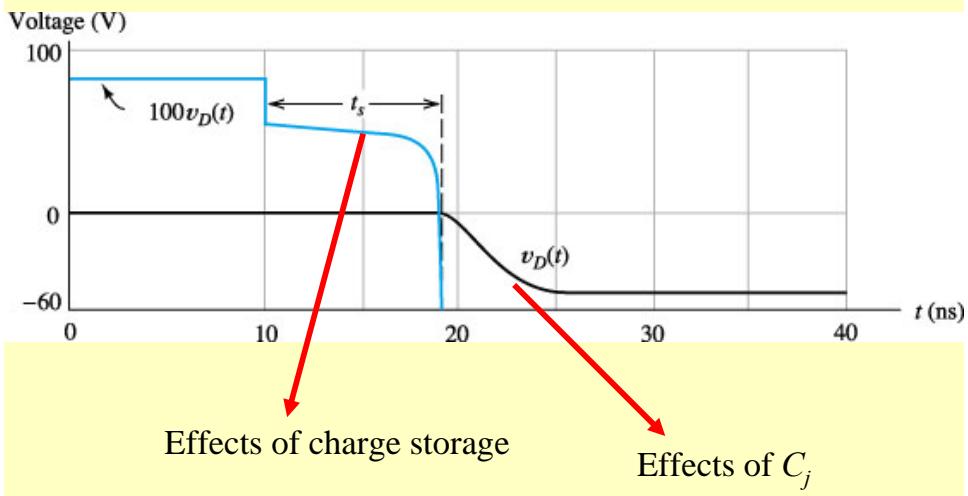
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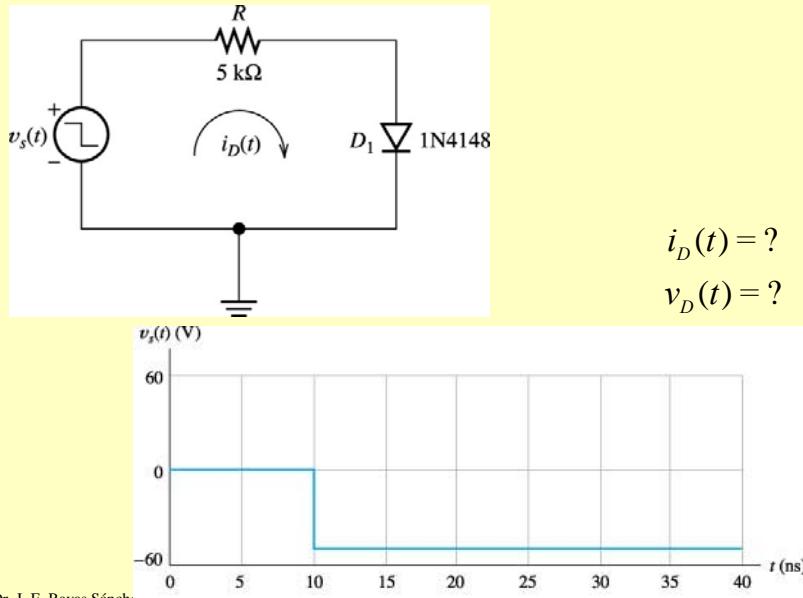
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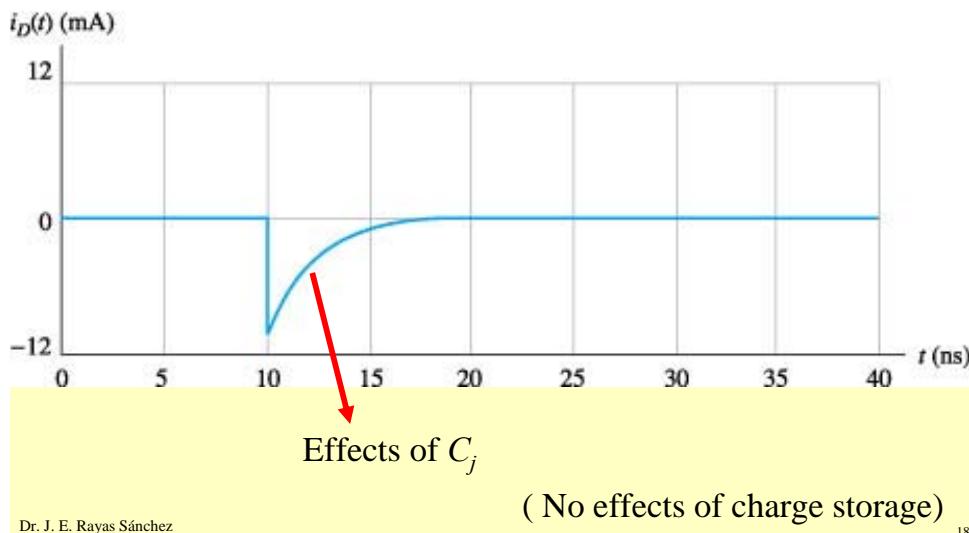
Effects of C_j , C_d , and Charge Storage – Ex. 2



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Effects of C_j , C_d , and Charge Storage – Ex. 2



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